Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/618,850	TANAKA ET AL.	
Examiner	Art Unit	
David Nhu	2818	

SEARCHED					
Class	Subclass	Date	Examiner		
438	30	7/6/2005	DN		
	45, 46	1			
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	154, 157				
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
438	30	11/13/2006	DN		
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SEARCHED IN EAST	7/6/2005	DN
SEARCHED IN EAST	6/12/2006	DN
SEARCHED IN EAST	11/13/2006	DN
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